

FIG.1

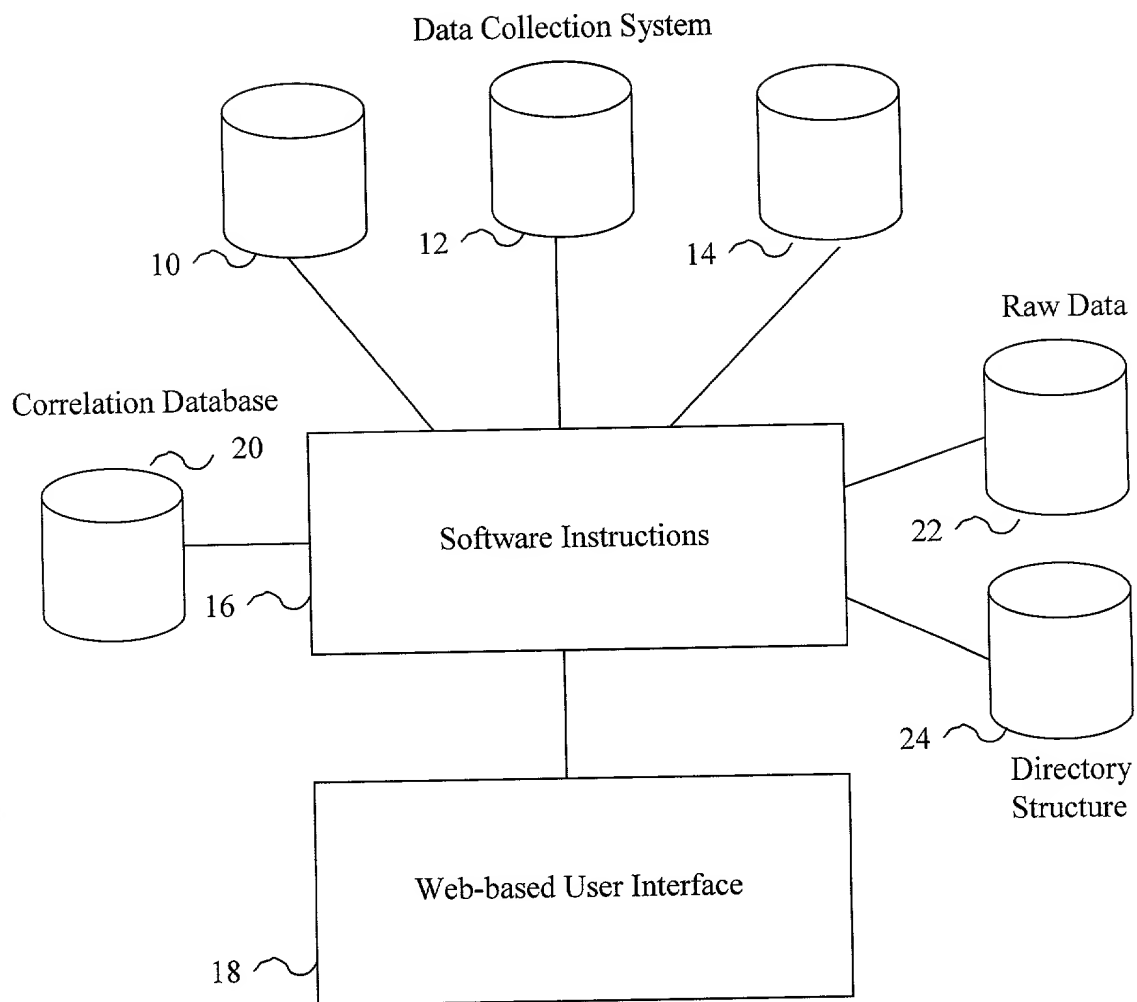


FIG.2

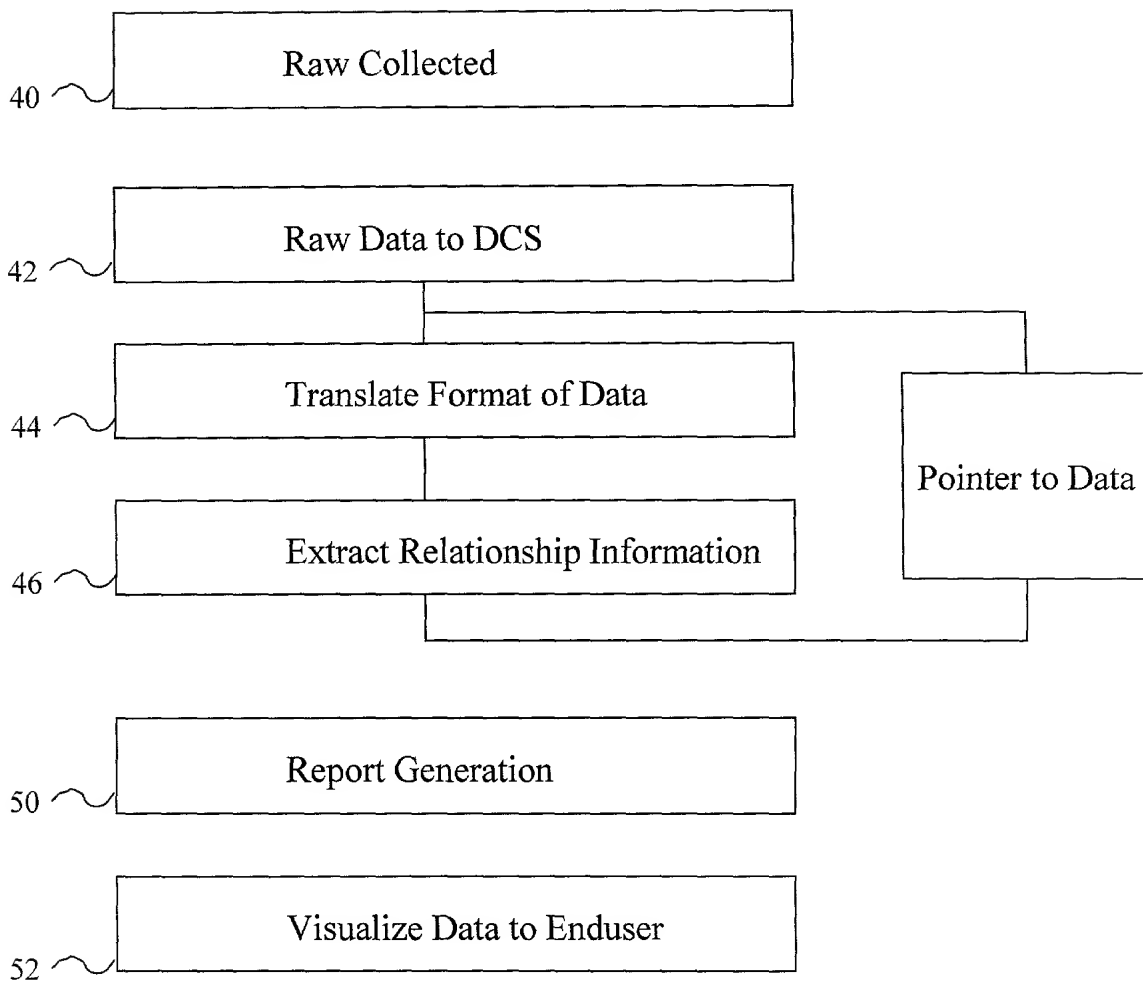


FIG.3

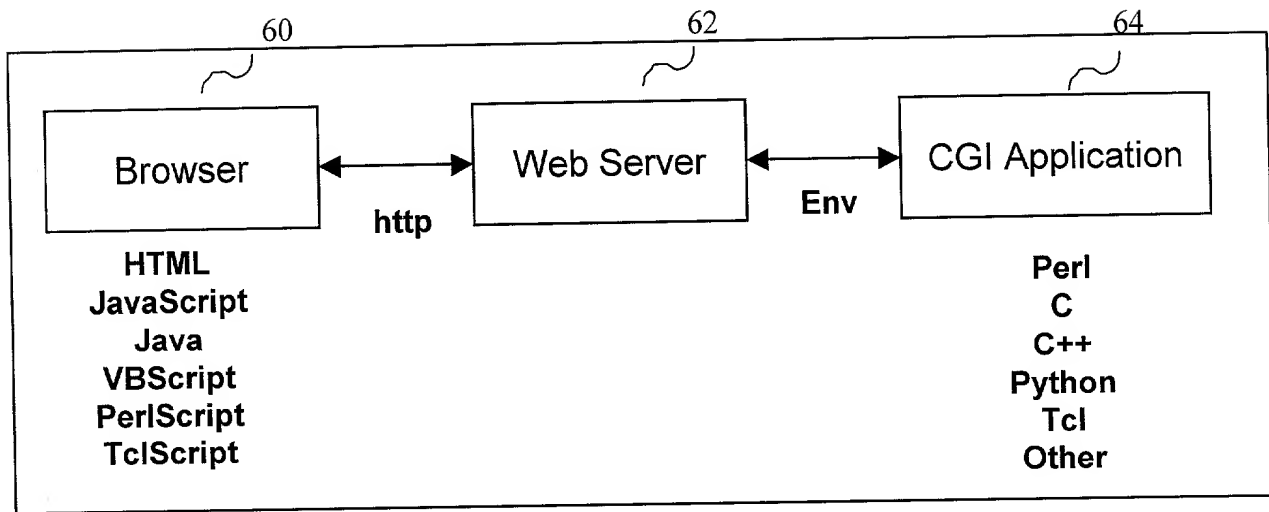


FIG.4

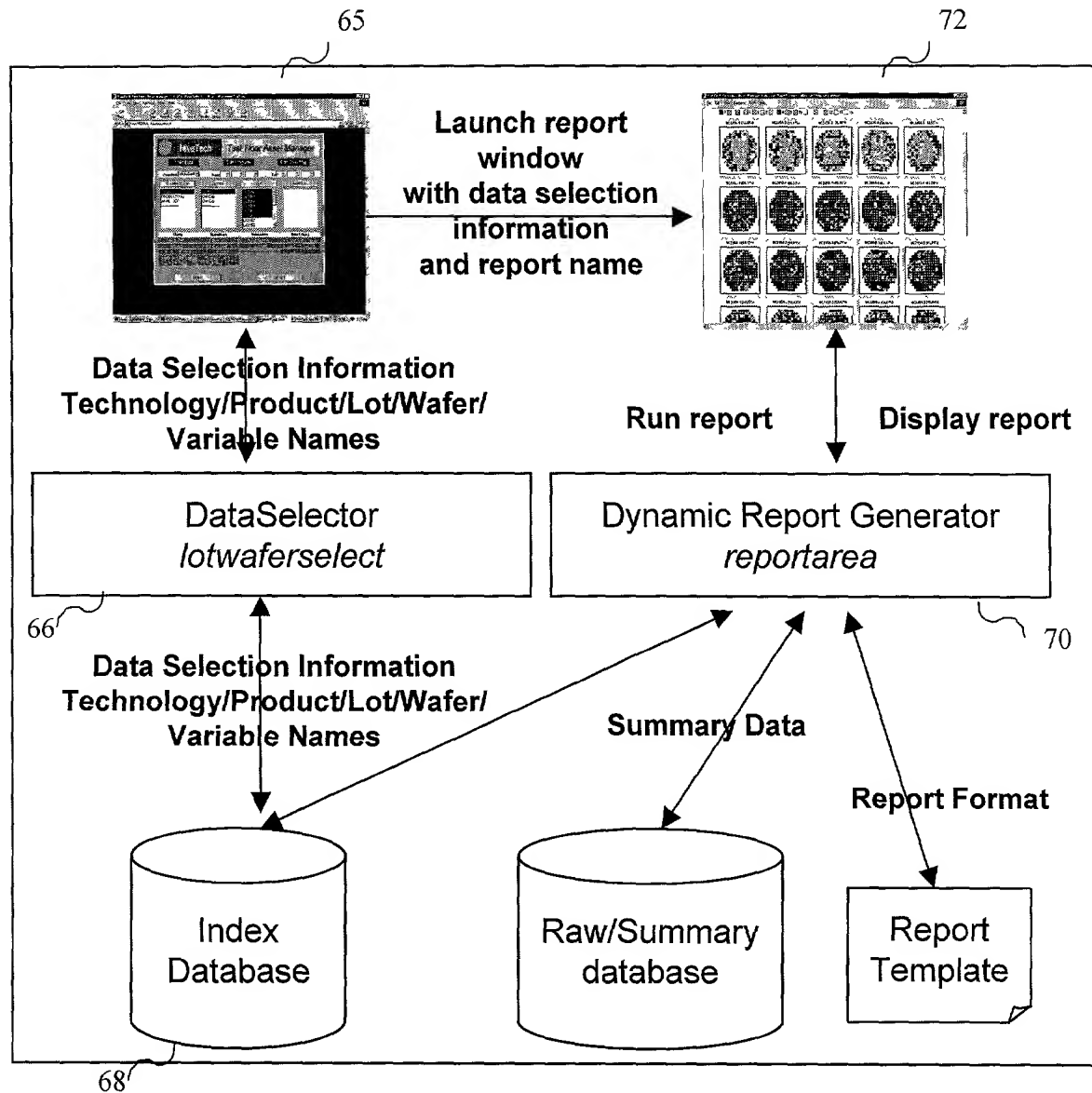


FIG.5

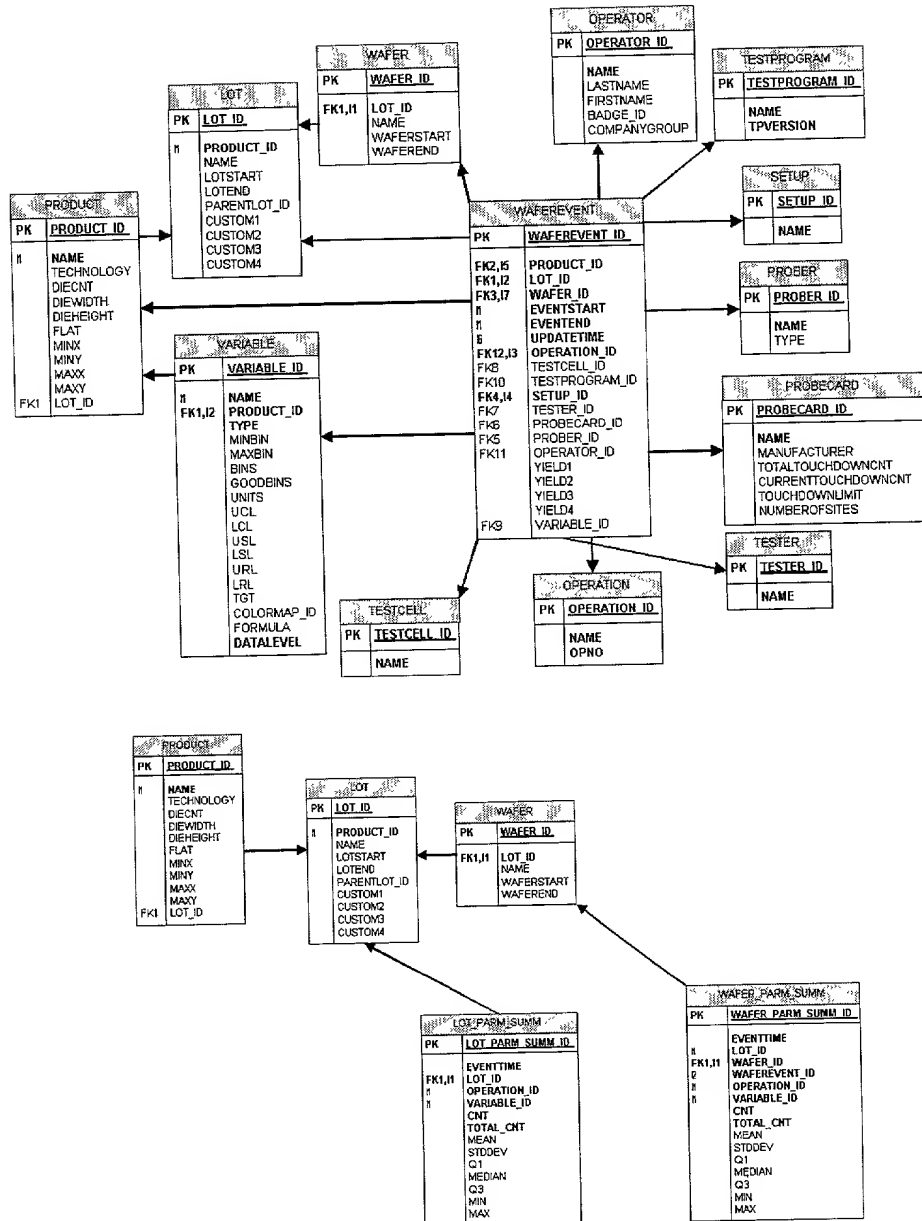


FIG.6

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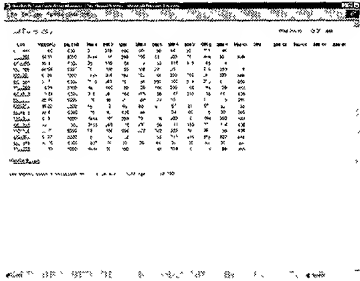
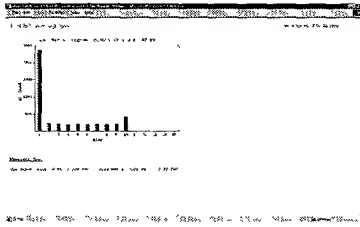
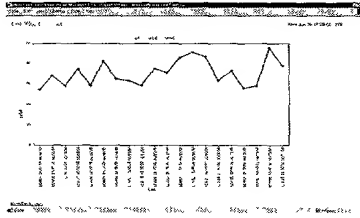
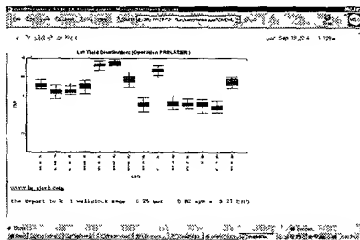
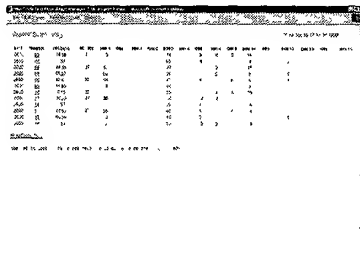
| Report Name | Report Description | Example |
|--------------------|---|--|
| Lot Summary | A tabular reports that displays the lot bin summary for the selected lots. Click on an individual lot name to drill down to a Wafer Summary report |  |
| Lot Bin Histogram | Bar chart of bin count totals for selected lots. |  |
| Lot Yield Trend | Line trend chart of lot yields of the selected lots. |  |
| Lot Yield Box Plot | Displays the distribution of wafer yields for the selected lots in a single report. The wafer yields are represented as a standard box plot. |  |
| Bin Summary | A tabular report that displays the wafer bin summary for the selected wafers. Click on an individual wafer name to drill down to a Bin Map report. |  |

FIG.7
(Sheet 1)

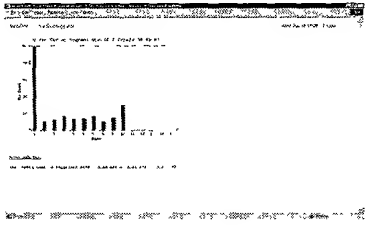
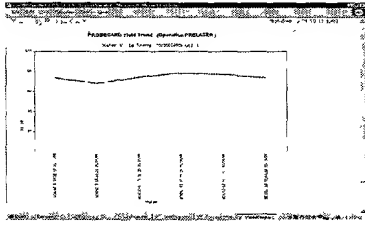
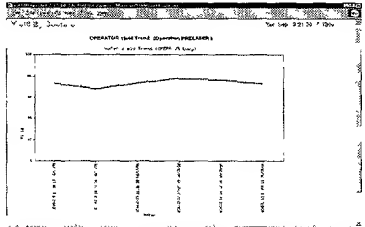
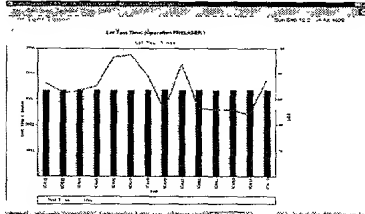
| Report Name | Report Description | Example |
|---------------------|--|--|
| Wafer Bin Histogram | Bar chart of bin count totals for selected wafers. |  |
| Yield by Probe Card | Line trend chart of wafer yields of all selected wafers, sorted by probe card. |  |
| Yield by Operator | Line trend chart of wafer yields of all selected wafers, sorted by operator. |  |
| Wafer Test Times | A bar chart that plots the actual time taken to test a wafer and the associated yield trend line for that wafer. | No Image Available |
| Lot Test Times | A bar chart that plots the actual time taken to test a lot, and the associated yield trend line for that lot. |  |

FIG.7
(Sheet 2)

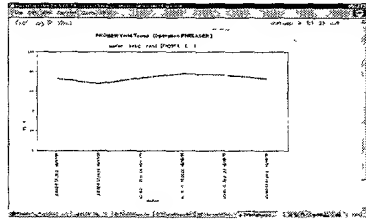
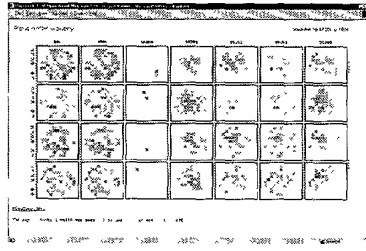
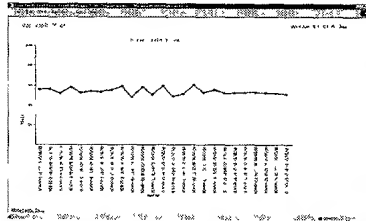
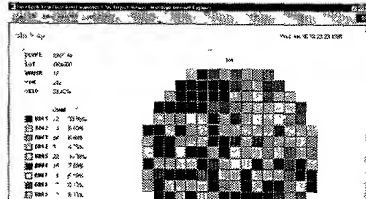
| Report Name | Report Description | Example |
|-------------------|--|--|
| Yield by Tester | Line trend chart of wafer yields of all selected wafers, sorted by tester. | No Image Available |
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| Yield by Prober | Line trend chart of wafer yields of all selected wafers, sorted by prober. |  |
| 86 | | |
| Parameter Gallery | Display a table of maps where each column is a parameter and each row is a wafer. Displays wafer maps for all parameters declared for the selected device. Click on an individual wafer map to zoom into that map. Use the browser "Back" button to return to the gallery. |  |
| Wafer Yield Trend | Line trend chart of wafer yields of the selected wafers. |  |
| Bin Map | Displays a bin map of the selected wafers. Displays maps for all wafers in the selected lots if no individual wafers are selected. |  |
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FIG.7
(Sheet 3)

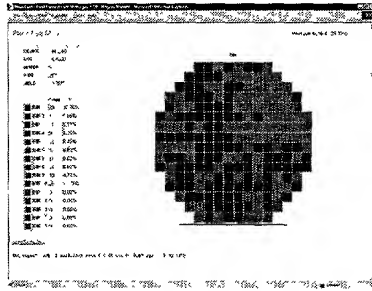
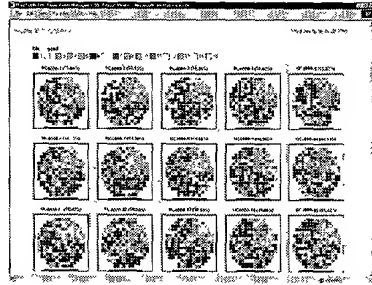
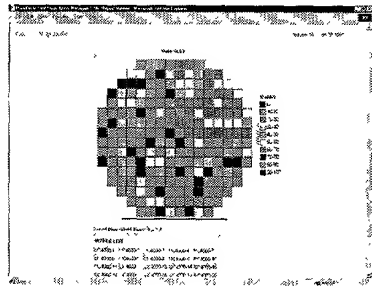
| Report Name | Report Description | Example |
|-------------------|---|--|
| Pass/Fail Bin Map | Displays a pass/fail map for the selected wafers. This report uses the device configuration information to determine the pass bins. Displays maps for all wafers in the selected lots if no individual wafers are selected. |  |
| Bin Gallery | Displays a pass/fail map for the selected wafers. Displays maps for all wafers in the selected lots if no individual wafers are selected. Click on an individual wafer map to zoom into that map. |  |
| Percent Composite | Displays a composite yield map for the selected wafers. This report uses the device configuration information to determine the pass bins. |  |

FIG.7
(Sheet 4)

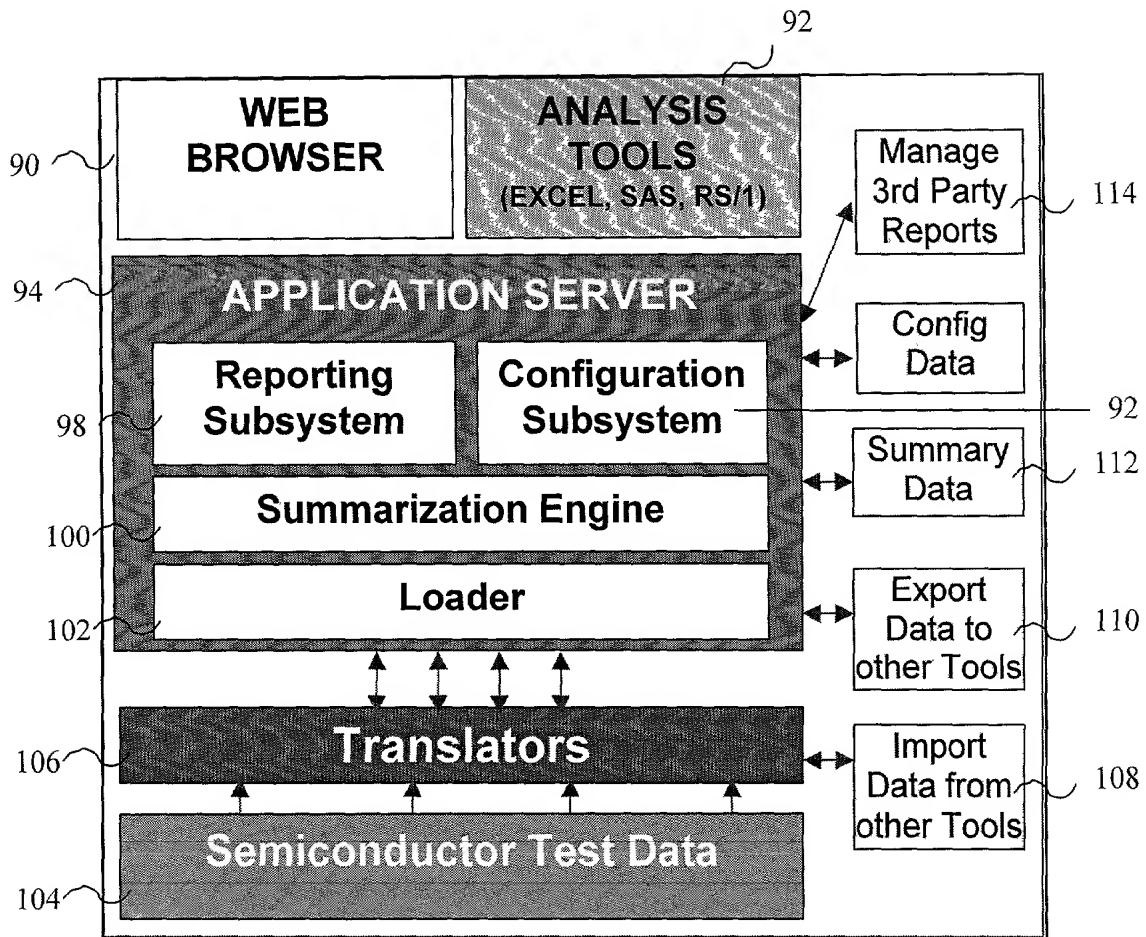


FIG.8

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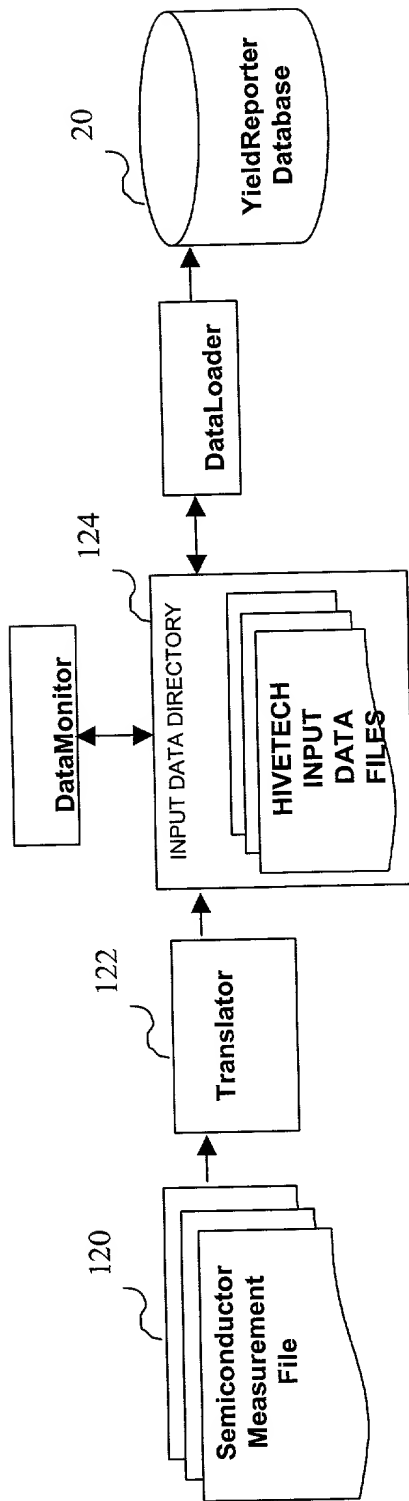
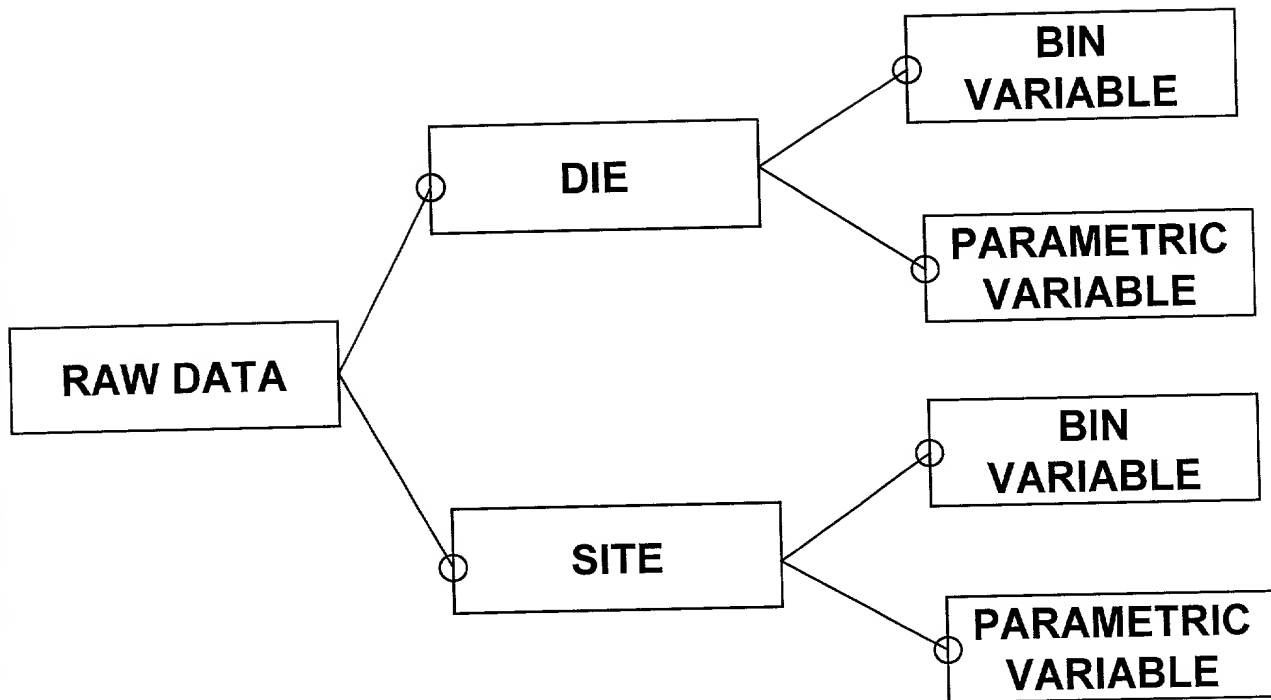
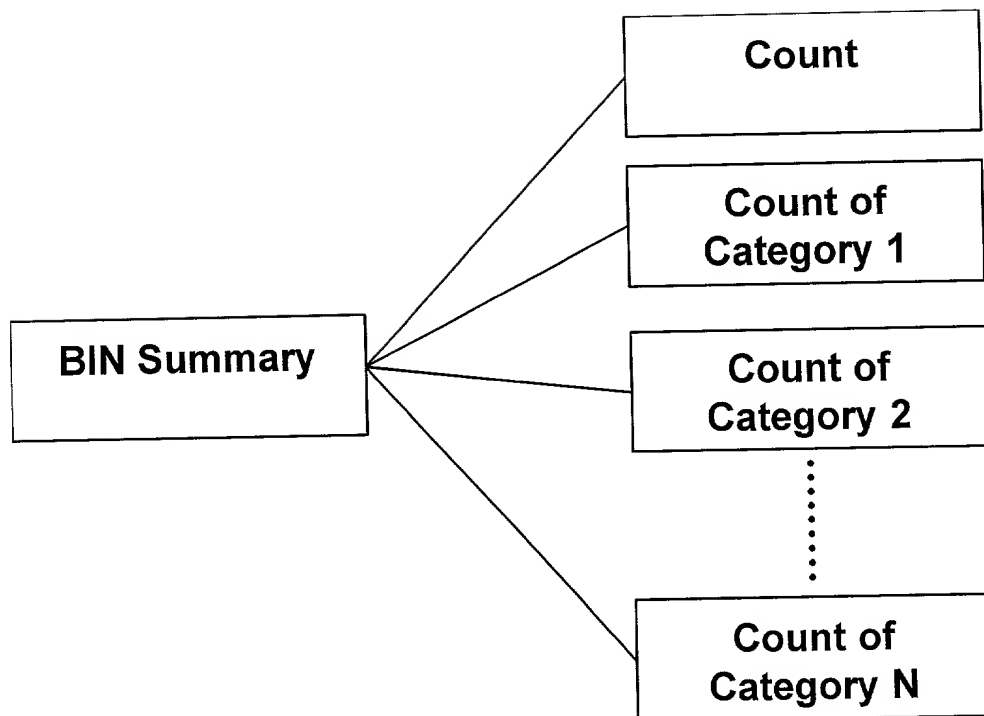


FIG.9



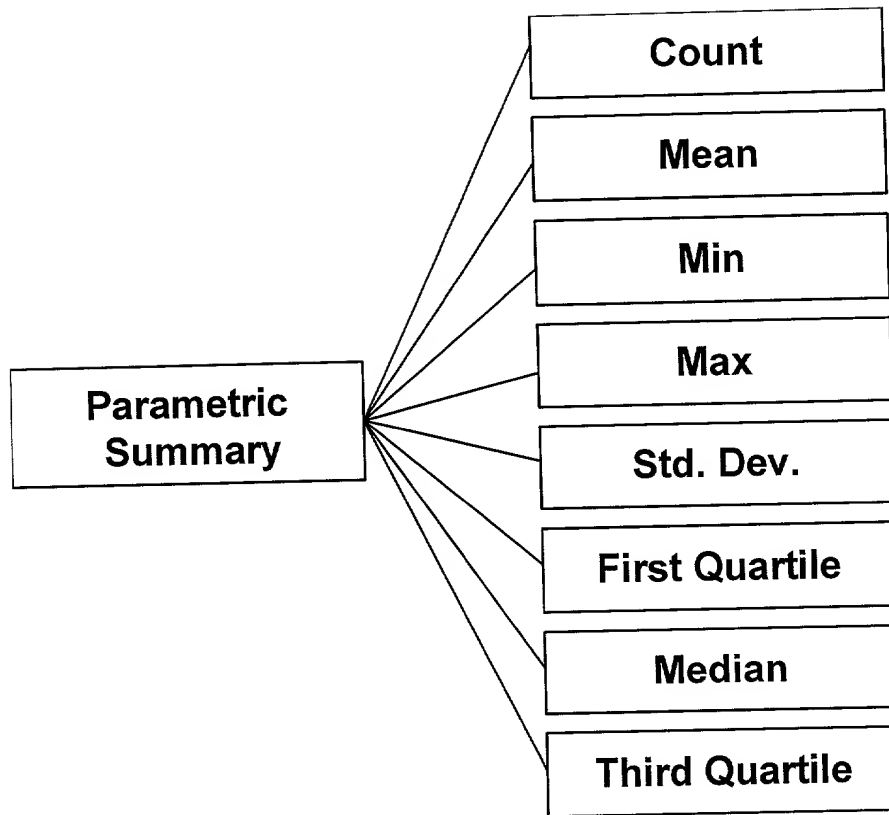
Variable Types

FIG.10A



Lot or Wafer Bin Summary

FIG.10B



Lot or Wafer Parametric Summary

FIG.10C